Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/670,427	TANAKA ET AL.	
Examiner	Art Unit	
18/22 de BA Nomeén	2022	

	SEAR	CHED	****
Class	Subclass	Date	Examiner
348	211.3	12/18/2006	WMN
348	211.1	12/19/2006	WMN
348	211.5	12/19/2006	WMN

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor name search	12/14/2006	WMN		
Please refer to attached EAST search report (DB: USPAT, USPGPUB, USOCR, FPRS, EPO, JPO, DERWENT, IBM_TDB)	12/18/2006	WMN		
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